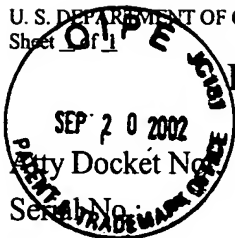


U. S. DEPARTMENT OF COMMERCE
Sheet 1 of 1

PATENT AND TRADEMARK OFFICE



LIST OF REFERENCES CITED BY APPLICANT

Patent Docket No.

5054-6PUS

Filing Date: 08 February 2002

Serial No.

10/049,314

Group Art: Not Yet Assigned

Applicant:

Johannes VÄÄNÄNEN

U.S. PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Name	Class	Subclass	Filing Date
<i>RLO</i>	AA	5,602,566	02/1997	Motosyuku et al.			
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Country	Name	Class	Subclass	Translation Yes/No
<i>RLO</i>	AF	WO 99/22338	05/1998	WIPO				
<i>RLO</i>	AG	WO 99/32960	07/1999	WIPO				
<i>RLO</i>	AH	10011249	01/1998	EPO				Yes
<i>RLO</i>	AI	2000259856	09/2000	EPO				Yes
	AJ							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AK		
	AL		
	AM		

EXAMINER:

Ricardo Garcia

DATE CONSIDERED:

11/15/03

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U. S. DEPARTMENT OF COMMERCE
Sheet 1 of 1

PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

Atty Docket No.: 5054-6PUS
Serial No.: 10/049,314
Applicant: Johannes VÄÄNÄNEN

Filing Date: 08 February 2002
Group Art: Not Yet Assigned

U.S. PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Name	Class	Subclass	Filing Date
RLO	AA	5,675,361	10/1997	Santilli			
RLO	AB	5,706,030	01/1998	Ishigami et al.			
RLO	AC	5,887,995	03/1999	Holehan			
RLO	AD	6,266,685	07/2001	Danielson et al.			
	AE						

FOREIGN PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Country	Name	Class	Subclass	Translation Yes/No
	AF							
	AG							
	AH							
	AI							
	AJ							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AK		
	AL		
	AM		

EXAMINER: *Richard O'Hara*

DATE CONSIDERED:

11/15/03

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF REFERENCES CITED BY APPLICANT

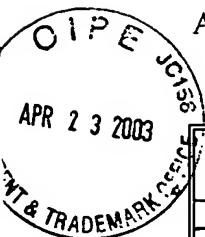
Atty Docket No.: 5054-6PUS

Filing Date: February 08, 2002

Serial No.: 10/049,314

Group Art: 2835

Applicant: Johannes VÄÄNÄNEN



U.S. PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Name	Class	Subclass	Filing Date
	AA	5,602,566	02/1997	Motosyuku et al.			
RLO	AB	6,201,554	03/2001	Lands			
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Country	Name	Class	Subclass	Translation Yes/No
RLO	AF	WO 98/14863	04/1998	WIPO				
RLO	AG	WO 01/78055	10/2001	WIPO				
RLO	AH	EP 0 805 378 A2	11/1997	EPO				
	AI							
	AJ							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AK		
	AL		
	AM		

EXAMINER: *Richard D. Davis*

DATE CONSIDERED: 11/14/03.

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

RECEIVED
199 24 2003
TECHNICAL SERVICES 2800